Abstracts

Design and On-Wafer Testing of Millimeter-Wave External Optical Modulators

D. Polifko, K. Matsui and H. Ogawa. "Design and On-Wafer Testing of Millimeter-Wave External Optical Modulators." 1993 MTT-S International Microwave Symposium Digest 93.3 (1993 Vol. III [MWSYM]): 1391-1394.

Highly accurate computation of the microwave refractive index and impedance of the coplanar waveguides on Ti:LiNbO3, Mach-Zehnder external optical modulators is performed using the extended spectral domain approach. Narrowband millimeter-wave modulators based on these calculations have been designed, fabricated, and tested with a novel on-wafer, 0-40GHz, optical and electrical probe station.

❑ Return to main document.

Click on title for a complete paper.